# **GSM3112Z**

# **30V N-Channel MOSFETs**

#### **Product Description**

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

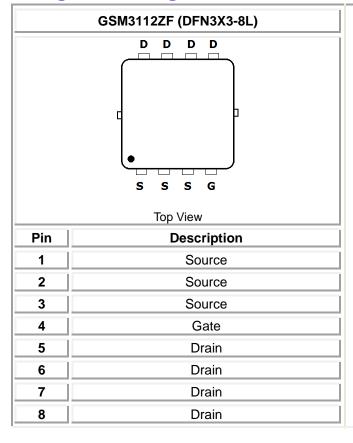
#### **Features**

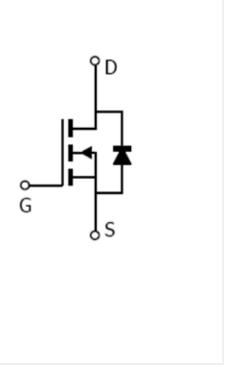
- 30V, 12.6A, R<sub>DS(ON)</sub>=10mΩ@V<sub>GS</sub>=10V
- Improved dv/dt capability
- Fast switching
- 100% EAS guaranteed
- Green Device Available

#### **Applications**

- MB / VGA / Vcore
- DC-DC Converters
- Power Management Functions

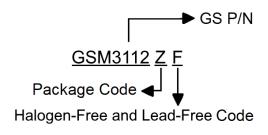
#### **Packages & Pin Assignments**





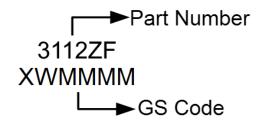


## **Ordering Information**



Part Number	Package	Quantity
GSM3112ZF	DFN3x3-8L	5000pcs

## **Marking Information**



#### **Absolute Maximum Ratings**

Tc=25°C Unless otherwise noted

Symbol	Parameter		Typical	Unit
V <sub>DS</sub>	Drain-Source Voltage		30	V
V <sub>G</sub> s	Gate-Source Voltage		±20	V
	Continuous Drain Current	T <sub>A</sub> =25°C	12.6	A
l <sub>D</sub>		T <sub>A</sub> =70°C	10	
I <sub>DM</sub>	Pulsed Drain Current <sup>1</sup>		45	Α
EAS	Single Pulse Avalanche Energy <sup>2</sup>		21	mJ
	Power Dissipation	T <sub>A</sub> =25°C	2.3	W
P <sub>D</sub>		T <sub>A</sub> =70°C	1.5	W/°C
TJ	Operating Junction Temperature Range		-55 to +150	$^{\circ}\mathbb{C}$
T <sub>STG</sub>	Storage Temperature Range		-55 to +150	$^{\circ}\mathbb{C}$
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient		53	°C/W
R <sub>eJC</sub>	Thermal Resistance-Junction to Case		4.7	°C/W



#### **Electrical Characteristics**

T<sub>J</sub>=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
	-	Static					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V	
$V_{GS(th)}$	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	1.2		2.5	V	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1	uA	
_		V <sub>GS</sub> =10V, I <sub>D</sub> =10A		7.9	10	mΩ	
R <sub>DS(on)</sub>	Drain-Source On-Resistance <sup>3</sup>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A,		13	16		
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A			10	S	
V <sub>SD</sub>	Diode Forward Voltage <sup>3</sup>	V <sub>GS</sub> =0V, I <sub>S</sub> =1A		0.7	1	V	
		Dynamic					
Qg	Total Gate Charge <sup>3,4</sup>			8		nC	
$Q_{gs}$	Gate-Source Charge <sup>3,4</sup>	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =12.5A		4			
$Q_{gd}$	Gate-Drain Charge <sup>3,4</sup>	ID-12.5A		2			
Ciss	Input Capacitance			1040			
Coss	Output Capacitance	V <sub>DS</sub> =15V,V <sub>GS</sub> =0V, f=1MHz		445		pF	
Crss	Reverse Transfer Capacitance	1=11/11/12		40			
t <sub>d(on)</sub>	Turn-On Time <sup>3,4</sup>			10			
tr	Rise Time <sup>3,4</sup>	V <sub>DD</sub> =15V, I <sub>D</sub> =12.5A,		9		ns	
t <sub>d(off)</sub>	Turn-Off Time <sup>3,4</sup>	V <sub>GS</sub> =10V, R <sub>G</sub> =6Ω		24			
t <sub>f</sub>	Fall Time <sup>3,4</sup>			8			
Rg	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		1.1		Ω	

#### Note:

- 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- 2.  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.3mH,  $I_{AS}$ =12A, Starting  $T_J$ =25 $^{\circ}$ C.
- 3. The data tested by pulsed , pulse width  $\,\leq\,\,$  300us , duty cycle  $\,\leq\,\,$  2%.
- 4. Essentially independent of operating temperature.



#### **Typical Performance Characteristics**

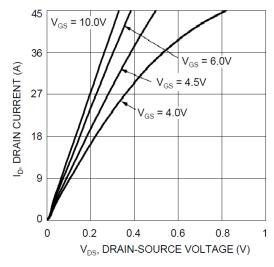


Fig. 1 Typical Output Characteristics

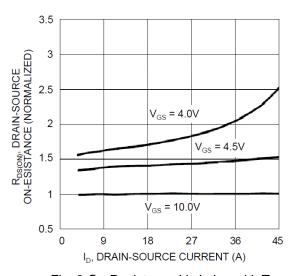


Fig. 3 On-Resistance Variation with  $T_{\mbox{\scriptsize A}}$ 

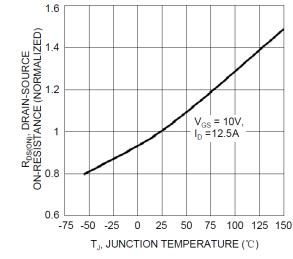


Figure. 5 On-Resistance Variation with T<sub>J</sub>

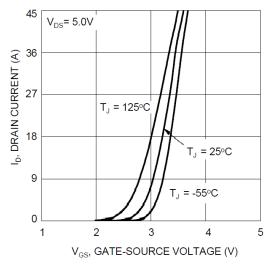


Fig. 2 Typical Transfer Characteristics

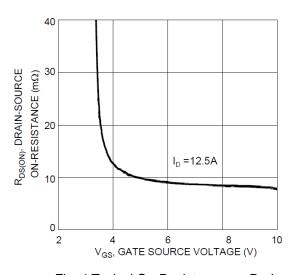


Fig. 4 Typical On-Resistance vs. Drain

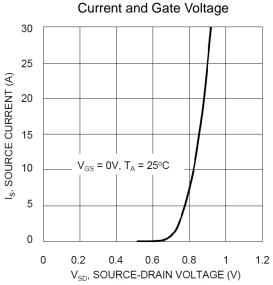


Fig. 6 Diode Forward Voltage vs. Current

## **Typical Performance Characteristics (Continue)**

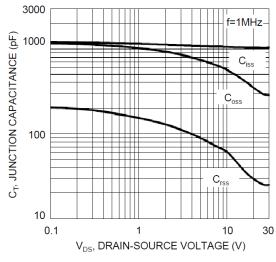


Fig. 7 Typical Capacitance

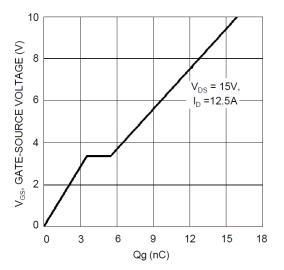
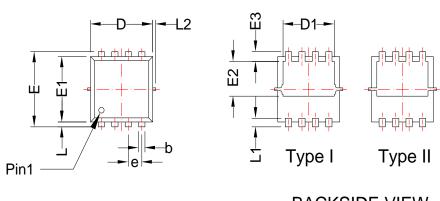


Fig. 8 Gate Charge



## **Package Dimension**

## DFN3X3-8L







DIMENSION D AND E1 DOES NOT INCLUDE MOLD FLASH,PROTRUSIONS OR GATE BURRS.MOLD FLASH,PROTRUSIONS OR GATE BURRS SHALL HOT EXCEED 0.5mm PER INTERLEAD FLASH OR PROTRUSIOB SHALL NOT EXCEED 0.5mm PER SIDE.

	Dimensions				
0	Millimeters		Inches		
Symbol	Min	Max	Min	Max	
Α	0.70	0.90	0.028	0.035	
<b>A</b> 1	0.00	0.05	0.000	0.002	
b	0.24	0.37	0.009	0.015	
С	0.10	0.25	0.004	0.010	
D	2.90	3.25	0.114	0.128	
D1	2.35	2.60	0.093	0.102	
Е	3.05	3.45	0.120	0.136	
E1	2.90	3.20	0.114	0.126	
E2	1.35	2.00	0.053	0.079	
E3	0.30	0.60	0.012	0.024	
е	0.65 BSC 0.026 BSC		BSC		
L	0.02	0.2	0.001	0.008	
L1	0.28	0.5	0.011	0.020	
L2		0.15		0.006	



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#### **CONTACT US**

	GS Headquarter		
\(\)	4F.,No.43-1,Lane11,Sec.6,Minquan E.Rd Neihu District Taipei City 114, Taiwan (R.O.C)		
<u>Fo</u>	886-2-2657-9980		
	886-2-2657-3630		
<u> </u>	sales_twn@gs-power.com		

	RD Division		
\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	824 Bolton Drive Milpitas. CA. 95035		
	1-408-457-0587		

